

IN THE CLAIMS:

Please amend claims 1, 22, and 26

Please cancel claims 18, 25, and 32-26 without prejudice.

Please add new claims 37-40.

Claims listing:

1. (Currently amended) A method comprising:
applying a first magnetic field to a magneto resistive memory cell; and
applying a second magnetic field to the magneto resistive memory cell;
wherein the first magnetic field failed to write a desired value to the magneto resistive memory cell, ~~and~~ wherein the second magnetic field is stronger than the first magnetic field and wherein the magneto resistive memory cell is one of a plurality of magneto resistive memory cells arrayed with a plurality of rows and a plurality of columns.
2. (Original) The method, as recited in Claim 1:
wherein applying the first magnetic field comprises applying a first current pulse having a first current level to a strip line of the magneto resistive memory cell;
wherein applying the second magnetic field comprises applying a second current pulse having a second current level to the strip line of the magneto resistive memory cell; and
wherein the second current level is higher than the first current level.
3. (Original) The method, as recited in Claim 2, wherein the first current level is less than six sigma above a mean switching current.
4. (Original) The method, as recited in Claim 2, wherein the first current level is less than a current level necessary to switch every stored value in a plurality of magneto resistive memory cells.

5. (Original) The method, as recited in Claim 2, wherein the strip line is a digit line for a plurality of magneto resistive memory cells.
6. (Original) The method, as recited in Claim 2, wherein the strip line is a row line for a plurality of magneto resistive memory cells.
7. (Original) The method, as recited in Claim 2, wherein the strip line is a bit line for a plurality of magneto resistive memory cells.
8. (Original) The method, as recited in Claim 2, wherein the strip line is a column line for a plurality of magneto resistive memory cells.
9. (Original) The method, as recited in Claim 1, further comprising:
performing a read of the magneto resistive memory cell to determine the stored value
prior to applying the first magnetic field; and
performing another read of the magneto resistive memory cell after applying the first
magnetic field.
10. (Original) The method, as recited in Claim 9, wherein the applying the first magnetic field occurs only if the stored value is not in a desired state.
11. (Original) The method, as recited in Claim 1, wherein applying the first magnetic field occurs during system test, the method further comprising:
determining that the first magnetic field is not sufficient to reliably write the desired
value; and
storing a result of the determination such that subsequent applications of magnetic fields
to the magneto resistive memory cell utilize a force level of the second magnetic
field.
12. (Original) The method, as recited in Claim 11, wherein storing the result comprises
setting a fuse.

13. (Original) The method, as recited in Claim 11, wherein storing the result comprises setting a memory bit.
14. (Original) The method, as recited in Claim 11, wherein storing the result comprises damaging a memory bit.
15. (Original) The method, as recited in Claim 11, wherein the subsequent applications of magnetic fields are applied to a row of magneto resistive memory cells.
16. (Original) The method, as recited in Claim 11, wherein the subsequent applications of magnetic fields are applied to a column of magneto resistive memory cells.
17. (Original) The method, as recited in Claim 1, wherein a structure of the magneto resistive memory cell structure comprises a magneto resistive memory element adjacent to a bit strip line and a digit strip line; and wherein applying current pulses to at least one of the word strip line and the digit strip line causes a value to be stored in the magneto resistive memory cell.
18. (Cancelled)
19. (Original) The method, as recited in Claim 1, wherein applying a first magnetic field comprises a toggle write mode.
20. (Original) The method, as recited in Claim 1, wherein applying a first magnetic field comprises a direct write mode.
21. (Original) The method, as recited in Claim 1, wherein applying a first magnetic field comprises a conventional write mode.

22. (Currently amended) A method comprising:
applying a first magnetic field to a plurality of magneto resistive memory cells during
system test ; and
determining that the first magnetic field is not sufficient to reliably write at least one of
the plurality of memory cells; and
storing a result of the determination such that subsequent applications of magnetic fields
to the select ones of the plurality of magneto resistive memory cells utilize a force
level of a second magnetic field; and
applying the a second magnetic field to select ones of the plurality of magneto resistive
memory cells;
wherein the first magnetic field failed to write a desired value to at least one stored value
in the select ones of the magneto resistive memory cells and wherein the second
magnetic field is stronger than the first magnetic field;.

23. (Original) The method, as recited in Claim 22, wherein the plurality of magneto
resistive memory cells are arranged in an array and the select ones of the plurality of
magneto resistive memory cells are a row of the array.

24. (Original) The method, as recited in Claim 23, wherein the first magnetic field has a
force less than a magnetic field necessary to reliably write the plurality of magneto
resistive memory cells.

25. (Cancelled)

26. (Currently amended) The method, as recited in Claim 22 25, wherein storing the
result comprises setting a fuse.

27. (Currently amended) The method, as recited in Claim 22 25, wherein storing the
result comprises setting a memory bit.

28. (Currently amended) The method, as recited in Claim 22-25, wherein storing the result comprises damaging a memory bit.

29. (Currently amended) The method, as recited in Claim 22-25, wherein the subsequent applications of magnetic fields are applied to a row of the plurality of magneto resistive memory cells.

30. (Original) The method, as recited in Claim 29, wherein the subsequent applications of magnetic fields are applied to a column of the plurality of magneto resistive memory cells.

31. (Currently amended) The method, as recited in Claim 22-25, wherein the subsequent applications of magnetic fields are applied to a column of the plurality of magneto resistive memory cells.

32. (Cancelled)

33. (Cancelled)

34. (Cancelled)

35. (Cancelled)

36. (Cancelled)

37. (New) A method comprising:

applying a first magnetic field to a magneto resistive memory cell; and

applying a second magnetic field to the magneto resistive memory cell;

wherein the first magnetic field failed to write a desired value to the magneto resistive memory cell, wherein the second magnetic field is stronger than the first magnetic field, wherein the magneto resistive memory cell is one of a plurality of magneto resistive memory cells arrayed with a plurality of rows and a plurality of columns,

and wherein applying the first magnetic field comprises a writing mode consisting from the group of a toggle write mode, a direct write mode and a conventional write mode.

38. (New) The method, as recited in Claim 37, wherein a first magnetic field is applied utilizing a toggle write mode.

39. (New) The method, as recited in Claim 37, wherein a first magnetic field is applied utilizing a direct write mode.

40. (New) The method, as recited in Claim 37, wherein a first magnetic field is applied utilizing a conventional write mode.